

64K (8K x 8) CMOS EEPROM

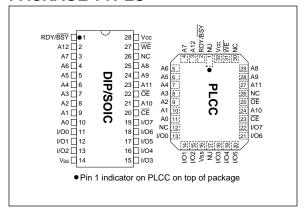
FEATURES

- Fast Read Access Time-150 ns
- · CMOS Technology for Low Power Dissipation
 - 30 mA Active
 - 100 μA Standby
- Fast Byte Write Time—200 μs or 1 ms
- Data Retention >200 years
- High Endurance Minimum 100,000 Erase/Write Cycles
- · Automatic Write Operation
 - Internal Control Timer
 - Auto-Clear Before Write Operation
 - On-Chip Address and Data Latches
- Data Polling
- Ready/Busy
- · Chip Clear Operation
- · Enhanced Data Protection
 - Vcc Detector
 - Pulse Filter
 - Write Inhibit
- Electronic Signature for Device Identification
- 5-Volt-Only Operation
- Organized 8Kx8 JEDEC Standard Pinout
 - 28-pin Dual-In-Line Package
 - 32-pin PLCC Package
 - 28-pin SOIC Package
- · Available for Extended Temperature Ranges:
 - Commercial: 0°C to +70°C
 Industrial: -40°C to +85°C

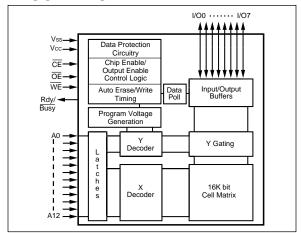
DESCRIPTION

The Microchip Technology Inc. 28C64A is a CMOS 64K nonvolatile electrically Erasable PROM. The 28C64A accessed like a static RAM for the read or write cycles without the need of external components. During a "byte write", the address and data are latched internally, freeing the microprocessor address and data bus for other operations. Following the initiation of write cycle, the device will go to a busy state and automatically clear and write the latched data using an internal control timer. To determine when the write cycle is complete, the user has a choice of monitoring the Ready/ Busy output or using Data polling. The Ready/Busy pin is an open drain output, which allows easy configuration in wiredor systems. Alternatively, Data polling allows the user to read the location last written to when the write operation is complete. CMOS design and processing enables this part to be used in systems where reduced power consumption and reliability are required. A complete family of packages is offered to provide the utmost flexibility in applications.

PACKAGE TYPES



BLOCK DIAGRAM



1.0 ELECTRICAL CHARACTERISTICS

1.1 MAXIMUM RATINGS*

Vcc and input voltagesw.r.t. V ss-0.6V to + 6.25V Voltage on $\overline{\text{OE}}$ w.r.t. Vss-0.6V to +13.5V Voltage on A9w.r.t. Vss-0.6V to +13.5V Output Voltage w.r.t. Vss-0.6V to V cc+0.6V Storage temperature-65°C to +125°C Ambient temp. with power applied-50°C to +95°C

*Notice: Stresses abve those listed unde "Maxi mum Ratings" may cause permanent damage to the evice. This is a stress ating only and functional operation of the device at those or any other conditions above those indicated in the operation listings of this specification is not implied Exposure to maximum rating conditions for extended periods may affect device reliability.

TABLE 1-1: PIN FUNCTION TABLE

Name	Function						
A0 - A12	Address Inputs						
CE	Chip Enable						
ŌĒ	Output Enable						
WE	Write Enable						
1/00 - 1/07	Data Inputs/Outputs						
RDY/Busy	Ready/Busy						
Vcc	+5V Power Supply						
Vss	Ground						
NC	No Connect No Internal Connection						
NU	Not Used No External Connection is All owed						

TABLE 1-2: READ/WRITE OPERATION DC CHARACTERISTIC

VCC = $+5V \pm 10\%$ Commercial (C): Tamb = 0° C to $+70^{\circ}$ C Industrial (I): Tamb = -40° C to $+85^{\circ}$ C

	Industrial (I): Tamb = -40°C to +						
Parameter	Status	Symbol	Min	Max	Units	Conditions	
Input Voltages	Logic '1' Logic '0'	VIH VIL	2.0 -0.1	Vcc+1 0.8	V V		
Input Leakage	_	ILI	-10	10	μΑ	VIN = -0.1V to Vcc +1	
Input Capacitance	_	CIN	_	10	pF	V IN = 0V; Tamb = 25°C; f = 1 MHz (Note 2)	
Output Voltages	Logic '1' Logic '0'	Voh Vol	2.4	0.45	V	IOH = -400 μA IOL = 2.1 mA	
Output Leakage	_	ILO	-10	10	μΑ	VOUT = -0.1V to Vcc +0.1V	
Output Capacitance	_	Соит	_	12	pF	V IN = 0V; Tamb = 25°C; f = 1 MHz (Note 2)	
Power Supply Current, Active	TTL input	b c	_	30	mA	f = 5 MHz (Note 1) VCC = 5.5V	
Power Supply Current, Standby	TTL input TTL input CMOS input	ICC(S)TTL ICC(S)TTL ICC(S)CMOS	_	2 3 100	mA mA μA	$\overline{CE} = VIH (0^{\circ}C \text{ to } +70^{\circ}C)$ $\overline{CE} = VIH (-40^{\circ}C \text{ to } +85^{\circ}C)$ $\overline{CE} = VCC-0.3 \text{ to } Vcc +1$ $\overline{OE} = \overline{WE} = Vcc$ All other inputs equal VCC or Vss	

Note 1: AC power supply current above 5MHz: 2mA/MHz.

2: Not 100% tested.

TABLE 1-3: READ OPERATION AC CHARACTERISTICS

AC Testing Waveform: VIH = 2.4V; VIL = 0.45V; VOH = 2.0V; VOL = 0.8V

Output Load: 1 TTL Load + 100 pF

Input Rise and Fall Times: 20 ns

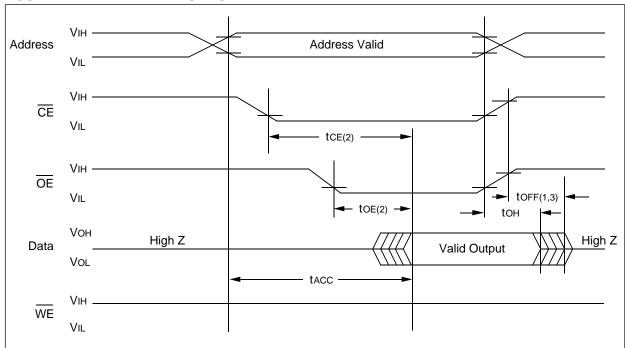
Ambient Temperature: Commercial (C): Tamb = 0° C to +70°C

Industrial (I): Tamb = -40° C to $+85^{\circ}$ C

Parameter	Symbol	28C64A-15		28C64A-20		28C64A-25		Units	Conditions
		Min	Max	Min	Max	Min	Max	Units	Conditions
Address to Output Delay	tACC	_	150	_	200	_	250	ns	$\overline{OE} = \overline{CE} = VIL$
CE to Output Delay	tCE	_	150	_	200	_	250	ns	OE = VIL
OE to Output Delay	tOE	_	70	_	80	_	100	ns	CE = VIL
CE or OE High to Output Float	toff	0	50	0	55	0	70	ns	(Note 1)
Output Hold from Address, $\overline{\text{CE}}$ or $\overline{\text{OE}}$, whichever occurs first.	tOH	0	_	0	_	0	_	ns	(Note 1)
Endurance	_	1M	_	1M	_	1M	_	cycles	25°C, Vcc = 5.0V, Block Mode (Note 2)

Note 1: Not 100% tested.

FIGURE 1-1: READ WAVEFORMS



Notes: (1) toff is specified for \overline{OE} or \overline{CE} , whichever occurs first

- (2) $\overline{\text{OE}}$ may be delayed up to tce toe after the falling edge of $\overline{\text{CE}}$ without impact on tce
- (3) This parameter is sampled and is not 100% tested

^{2:} This parameter is not tested but guaranteed by characterization. For endurance estimates in a specific application, please consult the Total Endurance Model which can be obtained on our BBS or website.

OE Hold Time

OE Set-Up Time

Data Valid Time

Time to Device Busy

Write Cycle Time (28C64A)

Write Cycle Time (28C64AF)

TABLE 1-4: BYTE WRITE AC CHARACTERISTICS

tWPH

tOEH

toes

tDV

tDB

twc

twc

AC Testing Waveform: VIH = 2.4V; VIL = 0.45V; VOH = 2.0V; VOL = 0.8VOutput Load: 1 TTL Load + 100 pF Input Rise/Fall Times: 20 ns Ambient Temperature: Commercial (C): 0°C to +70°C Tamb -40°C to +85°C Industrial Tamb **Parameter** Symbol Min Max Units Remarks Address Set-Up Time 10 tAS ns Address Hold Time tAH 50 ns Data Set-Up Time tDS 50 ns Data Hold Time tDH 10 ns Write Pulse Width 100 Note 1 **t**WPL ns Write Pulse High Time 50

10

10

2

ns

ns

ns

ns

ns

ms

μs

Note 2

0.5 ms typical

100 μs typical

1000

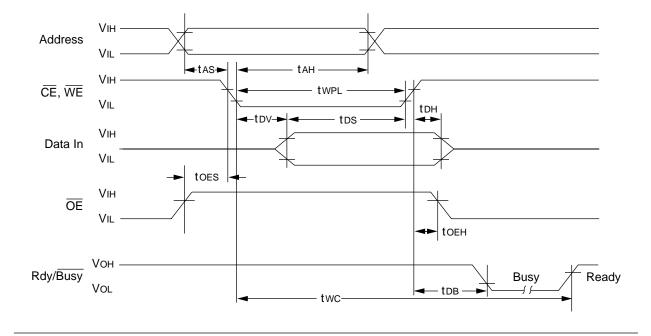
50

1

200

Note 1: A write cycle can be initiated be $\overline{\text{CE}}$ or $\overline{\text{WE}}$ going low, whichever occurs last. The data is latched on the positive edge WE, whichever occurs first.

FIGURE 1-2: **PROGRAMMING WAVEFORMS**



^{2:} Data must be valid within 1000ns max. after a write cycle is initiated and must be stable at least until tDH after the positive edge of WE or CE, whichever occurs first.

FIGURE 1-3: DATA POLLING WAVEFORMS

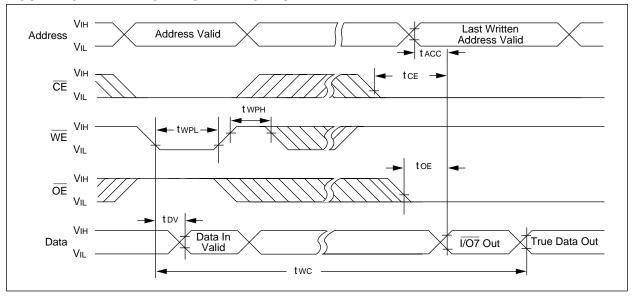


FIGURE 1-4: CHIP CLEAR WAVEFORMS

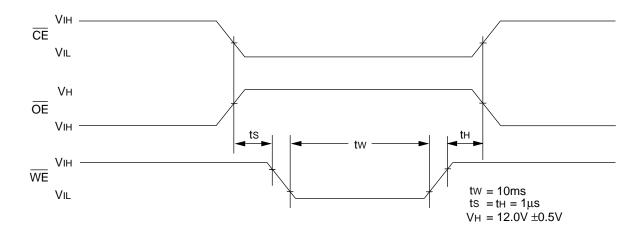


TABLE 1-5: SUPPLEMENTARY CONTROL

Mode	CE	ŌĒ	WE	A9	Vcc	I/Oı	
Chip Clear	VIL	VIH	VIL	Х	Vcc		
Extra Row Read	VIL	VIL	VIH	A9 = VH	Vcc	Data Out	
Extra Row Write	*	ViH	*	A9 = VH	Vcc	Data In	
Note: VH = 12.0V±0.5V. *Pulsed per programming waveforms.							

2.0 DEVICE OPERATION

The Microchip Technology Inc. 28C64A has four basic modes of operation—read, standby, write inhibit, and byte write—as outlined in the following table.

Operation Mode	CE	ŌĒ	WE	I/O	Rdy/Busy (1)		
Read	L	L	Н	Dout	Н		
Standby	Н	Х	Х	High Z	Н		
Write Inhibit	Н	Х	Х	High Z	Н		
Write Inhibit	Χ	L	Х	High Z	Н		
Write Inhibit	Х	Х	Н	High Z	Н		
Byte Write	L	Н	L	DIN	L		
Byte Clear	Automatic Before Each "Write"						

Note 1: Open drain output. 2: X = Any TTL level.

2.1 Read Mode

The 28C64A has two control functions, both of which must be logically satisfied in order to obtain data at the outputs. Chip enable (\overline{CE}) is the power control and should be used for device selection. Output Enable (\overline{OE}) is the output control and is used to gate data to the output pins independent of device selection. Assuming that addresses are stable, address access time (tACC) is equal to the delay from \overline{CE} to output (tCE). Data is available at the output toE after the falling edge of \overline{OE} , assuming that \overline{CE} has been low and addresses have been stable for at least tACC-toE.

2.2 Standby Mode

The 28C64A is placed in the standby mode by applying a high signal to the $\overline{\text{CE}}$ input. When in the standby mode, the outputs are in a high impedance state, independent of the $\overline{\text{OE}}$ input.

2.3 Data Protection

In order to ensure data integrity, especially during critical power-up and power-down transitions, the following enhanced data protection circuits are incorporated:

First, an internal Vcc detect (3.3 volts typical) will inhibit the initiation of non-volatile programming operation when Vcc is less than the Vcc detect circuit trip.

Second, there is a \overline{WE} filtering circuit that prevents \overline{WE} pulses of less than 10 ns duration from initiating a write cycle.

Third, holding \overline{WE} or \overline{CE} high or \overline{OE} low, inhibits a write cycle during power-on and power-off (Vcc).

2.4 Write Mode

The 28C64A has a write cycle similar to that of a Static RAM. The write cycle is completely self-timed and initiated by a low going pulse on the $\overline{\text{WE}}$ pin. On the falling edge of $\overline{\text{WE}}$, the address information is latched. On rising edge, the data and the control pins ($\overline{\text{CE}}$ and $\overline{\text{OE}}$) are latched. The Ready/Busy pin goes to a logic low level indicating that the 28C64A is in a write cycle which signals the microprocessor host that the system bus is free for other activity. When Ready/Busy goes back to a high, the 28C64A has completed writing and is ready to accept another cycle.

2.5 Data Polling

The 28C64A features Data polling to signal the completion of a byte write cycle. During a write cycle, an attempted read of the last byte written results in the data complement of I/O7 (I/O0 to I/O6 are indeterminable). After completion of the write cycle, true data is available. Data polling allows a simple read/compare operation to determine the status of the chip eliminating the need for external hardware.

2.6 <u>Electronic Signature for Device</u> <u>Identification</u>

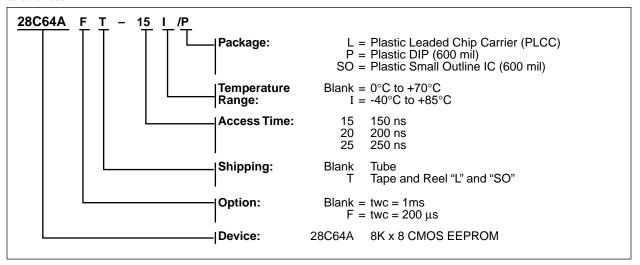
An extra row of 32 bytes of EEPROM memory is available to the user for device identification. By raising A9 to $12V \pm 0.5V$ and using address locations 1FEO to 1FFF, the additional bytes can be written to or read from in the same manner as the regular memory array.

2.7 Chip Clear

All data may be cleared to 1's in a chip clear cycle by raising \overline{OE} to 12 volts and bringing the \overline{WE} and \overline{CE} low. This procedure clears all data, except for the extra row.

28C64A Product Identification System

To order or to obtain information, e.g., on pricing or delivery, please use the listed part numbers, and refer to the factory or the listed sales offices.





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Microchip received ISO 9001 Quality System certification for its worldwide headquarters, design, and wafer fabrication facilities in January, 1997. Our field-programmable PICmicro™ 8-bit MCUs, Serial EEPROMs, related specialty memory products and development systems conform to the stringent quality standards of the International Standard Organization (ISO).

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